

Density-Gradient and Schrödinger—Poisson Results for a Silicon Inversion Layer

This tutorial demonstrates the use of the density-gradient formulation to include the effect of quantum confinement in the device physics simulation of a silicon inversion layer. This formulation requires only a moderate increase of computational resources as compared to the conventional drift—diffusion equation. Thus, it allows much speedier engineering investigation than other more sophisticated quantum mechanical methods. The result of the density-gradient theory is compared with the solution of the Schrödinger—Poisson equation. The computed electron density profiles from both theories show the expected behavior of quantum confinement and both agree well with the published figures in the reference paper.

Introduction

As the semiconductor fabrication technology progresses to produce smaller and smaller devices, the effect of quantum confinement becomes more and more important. This tutorial follows the approach described in Ref. 1 to compute the electron density distribution of a Si inversion layer using the density-gradient theory (as reviewed in Ref. 2) and to compare with the result from the self-consistent Schrödinger–Poisson theory.

Model Definition

The model aims to reproduce Fig. 4 in Ref. 1, which plots the electron density profiles underneath the gate oxide as computed with each of the two theories. Not all simulation details are given in the paper, especially the Schrödinger–Poisson simulator. Nevertheless, the approach described in the paper is followed as closely as possible. When a parameter is not listed, a typical value found in the literature is used in the model: the material properties of silicon and oxide are taken from Ref. 3; the parameters used for the Schrödinger–Poisson theory are taken from Ref. 4. The section Modeling Instructions lists all the parameters used in the model.

The oxide thickness is 3.1 nm and the doping concentration is $3.8 \cdot 10^{16}$ cm⁻³. The effective mass for the density-gradient formulation is 1/3 of the electron mass. The temperature is assumed to be 300 K. Fermi–Dirac statistics is used. The gate metal work function of 4.01 V is selected to match the peak electron densities shown in Fig. 4 in Ref. 1.

The Schrödinger–Poisson simulator used in Ref. 1 does not quantize the holes according to the author. Thus in this model we take the following strategy to treat the holes classically. First, both electron and hole concentrations are solved for using the density-gradient theory. Then, in the Schrödinger–Poisson equation, only the electron wave functions are solved for, with the hole concentration fixed to be the same as in the solution

of the density-gradient study. In other words, only the behavior of the electron gas is solved for using the two different methods and the two solutions will be compared.

See the comments in the section Modeling Instructions for more detailed discussions on the model construction, solution processes, and result visualization.

Results and Discussion

Figure 1 and Figure 2 show the electron density profiles for two values of gate voltage as computed by the two theories and at two different levels of zoom. They compare well with Fig. 4(a) and 4(b) in Ref. 1, respectively. The only difference is in the behavior of the Schrödinger-Poisson solution, which shows an abrupt drop off in the paper but not in this model. The drop off is just an artifact caused by the fact that an insufficient number of wave functions were used in the Schrödinger-Poisson simulator in the paper.

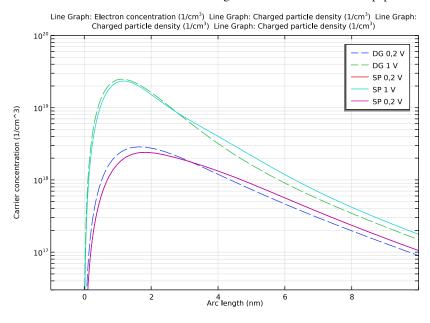


Figure 1: Electron density profiles for two values of gate voltage as computed using the two theories.

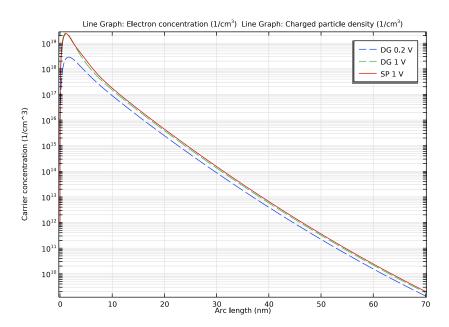


Figure 2: Zoomed-in version of the plot above.

References

- 1. M.G. Ancona, "Equations of State for Silicon Inversion Layers," *IEEE Trans. Elec. Dev.*, vol. 47, no. 7, p. 1449, 2000.
- 2. M.G. Ancona, "Density-gradient theory: a macroscopic approach to quantum confinement and tunneling in semiconductor devices," *J. Comput. Electron.*, vol. 10, p. 65, 2011.
- 3. S.M. Sze and K.K. Ng, Physics of Semiconductor Devices, 3rd ed., Wiley, 2007.
- 4. F. Stern, "Self-Consistent Results for n-Type Si Inversion Layers," *Phys. Rev. B*, vol. 5, no. 12, p. 4891, 1972.

Application Library path: Semiconductor_Module/Device_Building_Blocks/si_inversion_layer_density_gradient_and_schrodinger_poisson

From the File menu, choose New.

In the New window, click Model Wizard.

MODEL WIZARD

I In the Model Wizard window, click — ID.

Select the Semiconductor interface first. We will add the Schrödinger-Poisson Equation multiphysics interface later.

- 2 In the Select Physics tree, select Semiconductor>Semiconductor (semi).
- 3 Click Add.
- 4 Click Study.

The Semiconductor Equilibrium study step is suitable and easier to solve for systems known to be in thermal equilibrium.

- 5 In the Select Study tree, select Preset Studies for Selected Physics Interfaces> Semiconductor Equilibrium.
- 6 Click M Done.

GEOMETRY I

The Model Wizard starts the COMSOL Desktop at the Geometry node. Use this chance to select a convenient length unit. Then create the 1D geometry with a few consecutive intervals for easily plotting the results in various regions of interest.

- I In the Model Builder window, under Component I (compl) click Geometry I.
- 2 In the Settings window for Geometry, locate the Units section.
- 3 From the Length unit list, choose nm.

Interval I (i1)

- I Right-click Component I (compl)>Geometry I and choose Interval.
- 2 In the Settings window for Interval, locate the Interval section.
- **3** From the Coordinate source list, choose Vector.
- 4 In the Coordinates text field, type 0, 10, 70, 300, 1e3.

GLOBAL DEFINITIONS

Parameters for Density-Gradient

Enter the parameters for the density-gradient model.

- I In the Model Builder window, under Global Definitions click Parameters I.
- 2 In the Settings window for Parameters, type Parameters for Density-Gradient in the Label text field.
- **3** Locate the **Parameters** section. In the table, enter the following settings:

Name	Expression	Value	Description
T0	300[K]	300 K	Temperature
mnDG	me_const/3	3.0365E-31 kg	Density-gradient effective mass
Na0	3.8e16[1/cm^3]	3.8E22 I/m³	Doping concentration
Vg	0[V]	0 V	Gate voltage
epsr0x	3.9	3.9	Oxide dielectric constant
d0x	3.1[nm]	3.1E-9 m	Oxide thickness
Phi0	4.01[V]	4.01 V	Gate metal work function

Add a blank material and then fill in the material data.

MATERIALS

Material I (mat I)

- I In the Model Builder window, under Component I (compl) right-click Materials and choose Blank Material.
- 2 In the Settings window for Material, locate the Material Contents section.
- **3** In the table, enter the following settings:

Property	Variable	Value	Unit	Property group
Electron mobility	mun	1450[cm^2/ (V*s)]	m²/(V·s)	Semiconductor material
Hole mobility	mup	500[cm^2/ (V*s)]	m²/(V·s)	Semiconductor material

Property	Variable	Value	Unit	Property group
Relative permittivity	epsilonr_iso; epsilonrii = epsilonr_iso, epsilonrij = 0	11.9	I	Basic
Band gap	Eg0	1.12[V]	V	Semiconductor material
Electron affinity	chi0	4.05[V]	٧	Semiconductor material
Effective density of states, conduction band	Nc	2.80e19[cm ^-3]	I/m³	Semiconductor material
Effective density of states, valence band	Nv	2.65e19[cm ^-3]	I/m³	Semiconductor material

Set up physics formulations and parameters.

SEMICONDUCTOR (SEMI)

- I In the Model Builder window, under Component I (compl) click Semiconductor (semi).
- 2 In the Settings window for Semiconductor, locate the Model Properties section.
- 3 From the Carrier statistics list, choose Fermi-Dirac.
- 4 Click to expand the Discretization section. From the Formulation list, choose Finite element density-gradient (quadratic shape function).

Semiconductor Material Model I

- I In the Model Builder window, under Component I (compl)>Semiconductor (semi) click Semiconductor Material Model I.
- 2 In the Settings window for Semiconductor Material Model, locate the Model Input section.
- **3** In the T text field, type T0.
- **4** Locate the **Material Properties, Density-Gradient** section. In the $\mathbf{m}_e^{\ DG}$ text field, type mpDG

The holes are not treated quantum mechanically in the reference paper. Use an arbitrary large effective mass to minimize the effect of the density-gradient contribution from holes.

5 In the \mathbf{m}_h^{DG} text field, type 10*me_const.

Analytic Doping Model 1

I In the Physics toolbar, click — Domains and choose Analytic Doping Model.

- 2 In the Settings window for Analytic Doping Model, locate the Domain Selection section.
- 3 From the Selection list, choose All domains.
- **4** Locate the **Impurity** section. In the N_{A0} text field, type NaO.

Metal Contact I

- I In the Physics toolbar, click Boundaries and choose Metal Contact.
- 2 Select Boundary 5 only.

Thin Insulator Gate 1

- I In the Physics toolbar, click Boundaries and choose Thin Insulator Gate.
- 2 Select Boundary 1 only.
- 3 In the Settings window for Thin Insulator Gate, locate the Terminal section.
- **4** In the V_0 text field, type Vg.
- **5** Locate the **Gate Contact** section. In the ε_{ins} text field, type epsr0x.
- **6** In the d_{ins} text field, type d0x.
- **7** In the Φ text field, type Phi0.

The Schrödinger-Poisson computation in the reference paper assumes an infinite barrier height at the oxide interface. Use a large barrier height for electrons to approximate the infinite barrier limiting case. On the other hand, use zero barrier height for the holes to suppress the quantum confinement effect from the density-gradient formulation.

- 8 Locate the Density-Gradient section. From the Formulation list, choose Potential barrier.
- **9** In the Φ_n^{Ox} text field, type 1e4[V].
- **IO** In the Φ_p^{Ox} text field, type O[V].

MESH I

In the Model Builder window, under Component I (compl) right-click Mesh I and choose Edit Physics-Induced Sequence.

Size

- I In the Model Builder window, under Component I (compl)>Mesh I click Size.
- 2 In the Settings window for Size, locate the Element Size section.
- 3 From the Predefined list, choose Fine.

Remove artificial interior boundaries from the auto-generated list for mesh refinement.

Size 1

I In the Model Builder window, click Size I.

2 Select Boundary 5 only.

Specify a small mesh element size at the oxide interface to resolve the very large gradient there.

Size 2

- I In the Model Builder window, click Size 2.
- 2 In the Settings window for Size, locate the Element Size section.
- **3** Click the **Custom** button.
- 4 Locate the Element Size Parameters section.
- 5 Select the Maximum element size check box. In the associated text field, type 1e-4.

Add a **Size** node to prevent the mesh element size from growing too large in the regions of interest in which the results will be plotted.

Size 3

- I In the Model Builder window, right-click Mesh I and choose Size.
- 2 Right-click Size 3 and choose Move Up.
- 3 In the Settings window for Size, locate the Geometric Entity Selection section.
- 4 From the Geometric entity level list, choose Domain.
- **5** Select Domains 1–3 only.
- 6 Locate the Element Size section. From the Calibrate for list, choose Semiconductor.
- 7 From the Predefined list, choose Finer.
- 8 Click the **Custom** button.
- 9 Locate the Element Size Parameters section.
- 10 Select the Maximum element size check box. In the associated text field, type 0.5.

STUDY I: DENSITY-GRADIENT

- I In the Model Builder window, click Study I.
- 2 In the Settings window for Study, type Study 1: Density-Gradient in the Label text field.

Step 1: Semiconductor Equilibrium

- I In the Model Builder window, under Study I: Density-Gradient click
 - Step 1: Semiconductor Equilibrium.
- 2 In the Settings window for Semiconductor Equilibrium, click to expand the Study Extensions section.

- 3 Select the Auxiliary sweep check box.
- 4 Click + Add.

Start the gate voltage sweep at a value close to the flat band condition for easier convergence.

5 In the table, enter the following settings:

Parameter name	Parameter value list	Parameter unit
Vg (Gate voltage)	-1 0.2 1	V

- **6** In the table, click to select the cell at row number 1 and column number 3.
- 7 In the Home toolbar, click **Compute**.

RESULTS

Net Dopant Concentration (semi)

The model has a uniform p-doping therefore, we remove the generated default plot, Net Dopant Concentration.

I In the Model Builder window, under Results right-click Net Dopant Concentration (semi) and choose Delete.

Duplicate the plot group **Carrier Concentrations** to plot the electron density in the regions of interest to be compared with Fig.4 in the reference paper.

Carrier Concentrations (semi)

In the Model Builder window, under Results right-click Carrier Concentrations (semi) and choose Duplicate.

Electron Concentration Comparison

- I In the Model Builder window, under Results click Carrier Concentrations (semi) 1.
- 2 In the Settings window for ID Plot Group, type Electron Concentration Comparison in the Label text field.
- 3 Locate the Data section. From the Parameter selection (Vg) list, choose Manual.
- 4 In the Parameter indices (1-3) text field, type 2 3.

Hole Concentration

- I In the Model Builder window, expand the Electron Concentration Comparison node.
- 2 Right-click Hole Concentration and choose Delete.

Density-Gradient

The region of interest can be conveniently specified by selecting the domains to be plotted.

- I In the Model Builder window, under Results>Electron Concentration Comparison click **Electron Concentration.**
- 2 In the Settings window for Line Graph, locate the Selection section.
- 3 Click to select the Activate Selection toggle button.
- 4 Select Domains 1 and 2 only.
- 5 In the Label text field, type Density-Gradient. For easier comparison, make the plot line style the same as the one in the reference
- 6 Click to expand the Coloring and Style section. Find the Line style subsection. From the Line list, choose Dashed.
- 7 Click to expand the Legends section. From the Legends list, choose Automatic.
- 8 Find the Prefix and suffix subsection. In the Prefix text field, type DG.

Electron Concentration Comparison

I In the Model Builder window, right-click Electron Concentration Comparison and choose Duplicate.

Alternatively, the region of interest for plotting can be specified using the option Manual axis limits.

- 2 In the Model Builder window, click Electron Concentration Comparison.
- 3 In the Settings window for ID Plot Group, locate the Axis section.
- 4 Select the Manual axis limits check box.
- 5 In the x minimum text field, type -1.
- 6 In the x maximum text field, type 10.
- 7 In the y minimum text field, type 3e16.
- 8 In the y maximum text field, type 1e20.

For the Schrödinger-Poisson study, we take the approach that it shares the same hole and ionized dopant concentrations as the density-gradient study, such that the only difference between the two studies is the treatment of the electron distribution. As such, various results from the previous study will be taken as the inputs to the following setup steps where appropriate.

Now add the **Schrödinger-Poisson Equation** multiphysics interface. Remember to exclude **Study I** from the newly added interface.

ADD PHYSICS

- I In the Home toolbar, click Add Physics to open the Add Physics window.
- 2 Go to the Add Physics window.
- 3 Find the Physics interfaces in study subsection. In the table, clear the Solve check box for Study 1: Density-Gradient.
- 4 In the tree, select Semiconductor>Schrödinger-Poisson Equation.
- 5 Click Add to Component 1 in the window toolbar.
- 6 In the Home toolbar, click Add Physics to close the Add Physics window.

SCHRÖDINGER EQUATION (SCHR)

Add the parameters used by the Schrödinger-Poisson Equation multiphysics interface.

GLOBAL DEFINITIONS

Parameters for Schrödinger-Poisson

- I In the Home toolbar, click P Parameters and choose Add>Parameters.
- 2 In the Settings window for Parameters, type Parameters for Schrödinger-Poisson in the Label text field.
- **3** Locate the **Parameters** section. In the table, enter the following settings:

Name	Expression	Value	Description
nv	2	2	Valley degeneracy
fm3	0.916	0.916	Longitudinal effective mass factor
fm1	0.190	0.19	Transverse effective mass factor 1
fm2	0.190	0.19	Transverse effective mass factor 2
m3	fm3*me_const	8.3442E-31 kg	Longitudinal effective mass
m1	fm1*me_const	1.7308E-31 kg	Transverse effective mass 1
m2	fm2*me_const	1.7308E-31 kg	Transverse effective mass 2
md	sqrt(m1*m2)	1.7308E-31 kg	Density of states effective mass

Restrict the Schrödinger-Poisson Equation domain selection to a reasonable range near the oxide interface.

SCHRÖDINGER EQUATION (SCHR)

- I In the Model Builder window, under Component I (compl) click Schrödinger Equation (schr).
- 2 Select Domains 1–3 only.

ELECTROSTATICS (ES)

- I In the Model Builder window, under Component I (compl) click Electrostatics (es).
- 2 Select Domains 1–3 only.

SCHRÖDINGER EQUATION (SCHR)

Effective Mass 1

- I In the Model Builder window, under Component I (compl)>Schrödinger Equation (schr) click Effective Mass I.
- 2 In the Settings window for Effective Mass, locate the Effective Mass section.
- 3 In the $\mathbf{m}_{\text{eff.e.}11}$ text field, type m3.

Electron Potential Energy 1

- I In the Model Builder window, click Electron Potential Energy I.
- 2 In the Settings window for Electron Potential Energy, locate the Electron Potential Energy section
- **3** From the V_e list, choose **User defined**. In the associated text field, type **0**.

Specify the **Zero Probability** boundary condition at the oxide interface, to match the infinite barrier limiting case assumed by the reference paper.

Zero Probability I

- I In the Physics toolbar, click Boundaries and choose Zero Probability.
- 2 Select Boundary 1 only.

Use the density-gradient result for the initial guess electron density distribution, as well as the (fixed) space charge contribution from the holes and ionized dopants.

ELECTROSTATICS (ES)

In the Model Builder window, under Component I (compl) click Electrostatics (es).

Space Charge Density 1: initial electron density

- I In the Physics toolbar, click Domains and choose Space Charge Density.
- 2 In the Settings window for Space Charge Density, type Space Charge Density 1: initial electron density in the Label text field.

- 3 Locate the Domain Selection section. From the Selection list, choose All domains.
- **4** Locate the **Space Charge Density** section. In the ρ_v text field, type -e_const*semi.N.
- 5 Right-click Space Charge Density 1: initial electron density and choose Duplicate.

Space Charge Density 2: holes and ionized dopants

- I In the Model Builder window, under Component I (compl)>Electrostatics (es) click
 Space Charge Density I: initial electron density I.
- 2 In the Settings window for Space Charge Density, type Space Charge Density 2: holes and ionized dopants in the Label text field.
- 3 Locate the **Space Charge Density** section. In the ρ_v text field, type e_const*(semi.P+ semi.Ndplus-semi.Naminus).

Similarly use the density-gradient result for the electrostatics boundary conditions.

Electric Potential I

- I In the Physics toolbar, click Boundaries and choose Electric Potential.
- 2 Select Boundary 4 only.
- 3 In the Settings window for Electric Potential, locate the Electric Potential section.
- **4** In the V_0 text field, type -semi.Ec.

Electric Displacement Field I

- I In the Physics toolbar, click Boundaries and choose Electric Displacement Field.
- 2 Select Boundary 1 only.
- **3** In the **Settings** window for **Electric Displacement Field**, locate the **Electric Displacement Field** section.
- **4** Specify the \mathbf{D}_0 vector as

```
epsilonO_const*epsrOx*(Vg-(PhiO-semi.chi_semi)-V2)/dOx x
```

Set up the multiphysics coupling, again borrowing the result from the density-gradient simulation where appropriate.

MULTIPHYSICS

Schrödinger-Poisson Coupling I (schrp1)

- I In the Model Builder window, under Component I (compl)>Multiphysics click Schrödinger-Poisson Coupling I (schrpl).
- 2 In the Settings window for Schrödinger-Poisson Coupling, locate the Model Input section.

3 In the *T* text field, type T0.

The variable for the equilibrium Fermi level is not available in the current evaluation context. Thus we need to use the **withsol** operator to retrieve its value.

- **4** Locate the **Particle Density Computation** section. In the E_f text field, type e_const* withsol('sol1',semi.Ef_0,setval(Vg,Vg)).
- **5** In the m_d text field, type md.
- **6** In the g_i text field, type nv.

First use a **Stationary** study step to solve only the electrostatics physics to obtain a good initial condition for the fully coupled problem.

ADD STUDY

- I In the Home toolbar, click Add Study to open the Add Study window.
- 2 Go to the Add Study window.
- 3 Find the Studies subsection. In the Select Study tree, select General Studies>Stationary.
- **4** Find the **Physics interfaces in study** subsection. In the table, clear the **Solve** check boxes for **Semiconductor (semi)** and **Schrödinger Equation (schr)**.
- 5 Find the Multiphysics couplings in study subsection. In the table, clear the Solve check box for Schrödinger–Poisson Coupling I (schrp1).
- 6 Click Add Study in the window toolbar.
- 7 In the Home toolbar, click Add Study to close the Add Study window.

Use a **Parametric Sweep** node to set the gate voltage of 0.2 V for both subsequent study steps (one of them soon to be added).

STUDY 2

Parametric Sweep

- I In the Study toolbar, click Parametric Sweep.
- 2 In the Settings window for Parametric Sweep, locate the Study Settings section.
- 3 Click + Add.
- 4 In the table, enter the following settings:

Parameter name	Parameter value list	Parameter unit
Vg (Gate voltage)	0.2	V

5 In the table, click to select the cell at row number 1 and column number 3.

Use the **Values of variables not solved for** section to inherit the solution from the previous study. Make sure to select the solution corresponding to the same gate voltage of $0.2~\rm V$ as the one specified in the **Parametric Sweep** node previously.

Step 1: Stationary

- I In the Model Builder window, click Step 1: Stationary.
- 2 In the Settings window for Stationary, click to expand the Values of Dependent Variables section.
- **3** Find the **Values of variables not solved for** subsection. From the **Settings** list, choose **User controlled**.
- 4 From the Method list, choose Solution.
- 5 From the Study list, choose Study 1: Density-Gradient, Semiconductor Equilibrium.
- 6 From the Parameter value (Vg (V)) list, choose 0.2 V.
- 7 In the Model Builder window, click Study 2.
- 8 In the **Settings** window for **Study**, type Study 2: Schrödinger-Poisson Vg=0.2V in the **Label** text field.
- 9 Locate the Study Settings section. Clear the Generate default plots check box.

Add the dedicated **Schrödinger-Poisson** study step. For a completely new problem, it is often necessary to use the default **Manual** search option to find the range of the eigenenergies. Once the range is found, switch to the **Region** search option with appropriate settings for the range and number of eigenvalues, in order to ensure that all significant eigenstates are found by the solver.

Step 2: Schrödinger-Poisson

- I In the Study toolbar, click study Steps and choose Stationary>Schrödinger-Poisson.
- 2 In the Settings window for Schrödinger-Poisson, locate the Study Settings section.
- 3 From the Eigenvalue search method list, choose Rectangle.
- 4 In the Approximate number of eigenvalues text field, type 100.
- 5 In the Maximum number of eigenvalues text field, type 300.
- 6 Find the Elliptic search region subsection. From the Unit list, choose .
- 7 Find the Rectangle search region subsection. In the Smallest real part text field, type 0.1
- 8 In the Largest real part text field, type 1.
- 9 In the Smallest imaginary part text field, type -1e-7.

10 In the Largest imaginary part text field, type 1e-7.

Disable the space charge density contribution from the initial guess of the electron concentration.

- II Locate the Physics and Variables Selection section. Select the Modify model configuration for study step check box.
- 12 In the tree, select Component I (compl)>Electrostatics (es)> Space Charge Density 1: initial electron density.
- 13 Click O Disable.
- 14 Locate the Iterations section. From the Termination method list, choose Minimization of global variable.
- **I5** In the **Global variable** text field, type schrp1.global_err.
- 16 In the Absolute tolerance text field, type 1e-6.
- 17 Click to expand the Study Extensions section. Select the Auxiliary sweep check box.
- 18 Click + Add.
- **19** In the table, enter the following settings:

Parameter name	Parameter value list	Parameter unit
nv (Valley degeneracy)	2 4	

- **20** Click + **Add**.
- 21 In the table, enter the following settings:

Parameter name	Parameter value list	Parameter unit
fm3 (Longitudinal effective mass	0.916 0.190	
factor)		

- **2** Click + Add.
- **23** In the table, enter the following settings:

Parameter name	Parameter value list	Parameter unit
fm2 (Transverse effective mass factor 2)	0.190 0.916	

24 In the **Study** toolbar, click **Compute**.

Add the result to the electron concentration comparison plots.

RESULTS

Density-Gradient

In the Model Builder window, under Results>Electron Concentration Comparison right-click **Density-Gradient** and choose **Duplicate**.

Schrödinger-Poisson Vg=0.2V

- I In the Model Builder window, click Density-Gradient I.
- 2 In the Settings window for Line Graph, locate the Data section.
- 3 From the Dataset list, choose Study 2: Schrödinger-Poisson Vg=0.2V/Solution 2 (sol2).
- 4 In the Label text field, type Schrödinger-Poisson Vg=0.2V.
- 5 Locate the y-Axis Data section. In the Expression text field, type schrp1.n sum.
- 6 Locate the Coloring and Style section. Find the Line style subsection. From the Line list, choose Solid.
- 7 Locate the Legends section. From the Legends list, choose Manual.
- **8** In the table, enter the following settings:

Legends SP 0.2 V

9 Right-click Schrödinger-Poisson Vg=0.2V and choose Copy.

Electron Concentration Comparison

In the Model Builder window, right-click Electron Concentration Comparison and choose Paste Line Graph.

Schrödinger-Poisson Vg=0.2V

Duplicate the steps with some modifications for the case of gate voltage of 1.0 V.

ADD STUDY

- I In the Study toolbar, click Add Study to open the Add Study window.
- 2 Go to the Add Study window.
- 3 Find the Studies subsection. In the Select Study tree, select Empty Study.
- 4 Click Add Study in the window toolbar.
- 5 In the Study toolbar, click Add Study to close the Add Study window.

STUDY 2: SCHRÖDINGER-POISSON VG=0.2V

Parametric Sweep, Step 1: Stationary, Step 2: Schrödinger-Poisson

- I In the Model Builder window, under Study 2: Schrödinger-Poisson Vg=0.2V, Ctrl-click to select Parametric Sweep, Step 1: Stationary, and Step 2: Schrödinger-Poisson.
- 2 Right-click and choose Copy.

STUDY 3: SCHRÖDINGER-POISSON VG=I.OV

- I In the Model Builder window, right-click Study 3 and choose Paste Multiple Items.
- 2 In the Model Builder window, click Study 3.
- 3 In the Settings window for Study, type Study 3: Schrödinger-Poisson Vg=1.0V in the Label text field.
- 4 Locate the Study Settings section. Clear the Generate default plots check box.

Parametric Sweep

- I In the Model Builder window, under Study 3: Schrödinger-Poisson Vg=1.0V click Parametric Sweep.
- 2 In the Settings window for Parametric Sweep, locate the Study Settings section.
- **3** In the table, enter the following settings:

Parameter name	Parameter value list	Parameter unit
Vg (Gate voltage)	1.0	V

4 In the table, click to select the cell at row number 1 and column number 3.

Step 1: Stationary

- I In the Model Builder window, click Step I: Stationary.
- 2 In the Settings window for Stationary, locate the Values of Dependent Variables section.
- 3 Find the Values of variables not solved for subsection. From the Parameter value (Vg (V)) list, choose I V.
- 4 In the Study toolbar, click **Compute**.

RESULTS

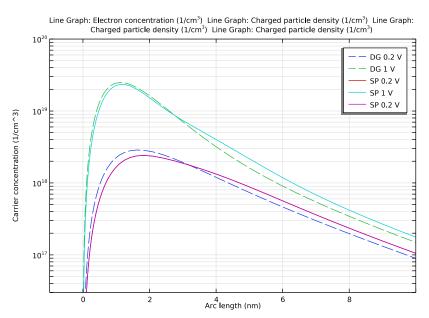
Schrödinger-Poisson Vg=0.2V

In the Model Builder window, under Results>Electron Concentration Comparison right-click **Schrödinger-Poisson Vg=0.2V** and choose **Duplicate**.

Schrödinger-Poisson Vg=1.0V

- I In the Model Builder window, under Results>Electron Concentration Comparison click Schrödinger-Poisson Vg=0.2V I.
- 2 In the Settings window for Line Graph, type Schrödinger-Poisson Vg=1.0V in the Label text field.
- 3 Locate the Data section. From the Dataset list, choose Study 3: Schrödinger-Poisson Vg=1.0V/Solution 8 (sol8).
- **4** Locate the **Legends** section. In the table, enter the following settings:

Legends SP 1 V



6 Right-click Schrödinger-Poisson Vg=1.0V and choose Copy.

Electron Concentration Comparison I

In the Model Builder window, under Results right-click Electron Concentration Comparison I and choose Paste Line Graph.

Schrödinger-Poisson Vg=1.0V

I In the Model Builder window, click Schrödinger-Poisson Vg=1.0V.

2 In the Electron Concentration Comparison I toolbar, click Plot.

